

<b>Notice of References Cited</b>	Application/Control No. 10/027,327	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Katarzyna Wyrozebski Lee	Art Unit 1714	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,811,491	09-1998	Jagawa et al.	525/71
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP 05-331335	12-1993	JP		
	O	JP 07-33484	02-1995	JP		
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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